## Notice of References Cited Application/Control No. 10/595,439 Examiner CATHERINE THIAW Applicant(s)/Patent Under Reexamination WOON ET AL. Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0203931	10-2004	Karaoguz, Jeyhan	455/457
*	В	US-5,926,117	07-1999	Gunji et al.	340/988
*	С	US-2003/0114981	06-2003	Allen et al.	701/213
*	D	US-2003/0109270	06-2003	Shorty, Peter	455/517
*	Е	US-7,123,925	10-2006	Robinson et al.	455/456.1
*	F	US-2002/0165645	11-2002	Kageyama, Masato	701/1
	G	US-			
	Ι	US-			
	-	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	w	
	х	

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